

FORM PTO-1449		Atty. Docket No.: 03-2477/L13.12-0258	Appl. No.: 10/817,419
<p style="text-align: center;">LIST OF PATENTS AND PUBLICATIONS FOR APPLICANT'S INFORMATION DISCLOSURE STATEMENT</p> 		First Named Inventor:	
		Judy M. Gehman et al.	
		Filing Date	Group Art:
April 1, 2004			

U.S. PATENT DOCUMENTS

Examiner Initial	Document No.	Date	Name	Class	Sub Class	Filing Date If Appropriate
/JV/ AA	6,574,778	06/2003	Chang et al.	716	1	
	AB	6,578,174	Zizzo	716	1	
	AC	6,536,028	Katsioulas et al.	716	17	
↓	AD	6,530,074	Katsioulas et al.	716	17	
↓	AE	6,366,874	Lee et al.	703	14	
/JV/ AF	6,334,207	12/2001	Joly et al.	716	17	

FOREIGN PATENT DOCUMENTS

		Document No.	Date	Country	Class	Sub Class	Translation Yes No
	AG						

OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)

/JV/ AH	Sutherland, S.; "The IEEE Verilog 1364-2001 Standard What's New, and Why You Need It," 9th Annual International HDL Conference and Exhibition, March 2000. Pp. 1-8.
	Cummings, C.; "Verilog-2001 Behavioral and Synthesis Enhancements," Revised April 2002, pp. 1-23.
	Cummings, C.; "New Verilog-2001 Techniques for Creating Parameterized Models (or Down with 'define and Death of a defparam!') HDLCON 2002, pp. 1-10.
	Wu, Y.; and MacDonald, P.; "Testing ASICs with Multiple Identical Cores," IEEE Transactions on Computer-Aided Design of Integrated Circuits and Systems, vol. 22, no. 3, March 2003, pp. 327-336.
↓ AJ	Miodrag Potkonjak et al. "Behavioral Synthesis of Area-Efficient Testable Designs Using Interaction Between Hardware Sharing and Partial Scan," IEEE Transactions on Computer-Aided Design of Integrated Circuits and Systems, vol. 14, no. 9, September 1995, pp. 1141-1154.
/JV/ AL	Chih-Chang Lin et al. "Test-Point Insertion: Scan Paths Through Functional Logic," IEEE Transactions on Computer-Aided Design of Integrated Circuits and Systems, vol. 17, no. 9, September 1998, pp. 838-851.

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AM						
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AQ						
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	AS						

OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)

/JV/	AT	Claus Schneider et al. "Modular Metrology Tools for Productivity Enhancement in Wafer Fabs," IEEE International Symposium on Semiconductor Manufacturing, Conference Proceedings, 1997. Oct. 6-8, 1997. Pp. B21-24.
/JV/	AU	Tianhao Zhang et al. "Design of Reconfigurable Composite Microsystems Based on Hardware/Software Codesign Principles," IEEE Transactions on Computer-Aided Design of Integrated Circuits and Systems, vol. 21, no. 8, Aug. 2002, pp. 987-995.
/JV/	AV	Ryota Kasai et al. "An Integrated Modular and Standard Cell VLSI Design Approach," IEEE Journal of Solid-State Circuits, vol. SC-20, no. 1, Feb. 1985 pp. 407-412.
/JV/	AW	Jeff Vanderlip. "LSI Logic Physical RTL Optimization (LSI PRO)," LSI Logic Corporation, Oct. 31, 2002. Pp. 1-7.
	AX	

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